

**AFM AND ELECTROCHEMISTRY**

HOLÁŇ Jakub

*Measurement Technic Moravia Ltd., Zastavka u Brna, Czech Republic, EU***Abstract**

This workshop is aimed to demonstrate advanced scanning probe microscopy techniques with combination of the electrical and electrochemical properties of various samples. We will show also the hot-news from Bruker – nanoscale Scanning Electrochemical Microscopy. We would like to show combination of the topography measurement with mechanical and electrical / electrochemical properties.

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